

### **Description**

The AP30N06DF uses advanced trench technology to provide excellent R<sub>DS(ON)</sub>, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### **General Features**

 $V_{DS} = 60V I_{D} = 30A$ 

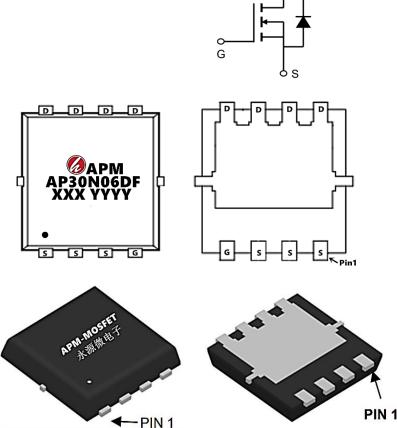
 $R_{DS(ON)}$  <36m $\Omega$  @  $V_{GS}$ =10V (Type: 28m $\Omega$ )

#### **Application**

LED lamp

Load switch

Uninterruptible power supply



**Package Marking and Ordering Information** 

Product ID	Pack	Marking	Qty(PCS)
AP30N06DF	PDFN-3*3-6L	AP30N06DF XXX YYYY	5000

Symbol	Parameter	Max.	Units
VDSS	Drain-Source Voltage	60	V
VGSS	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	30	А
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	16	A
IDM	Pulsed Drain Current	74	A
IAS	Avalanche Current	13	A
EAS	Single Pulsed Avalanche Energy	22	mJ
P <sub>D</sub> @T <sub>C</sub> =25°C	Power Dissipation	31.3	W
TJ, TSTG	Operating and Storage Temperature Range	-55 to +175	℃
$R_{\theta}JA$	Thermal Resistance Junction-Ambient <sup>1</sup>	62.5	°C/W
R₀JC	Thermal Resistance Junction-Case <sup>1</sup>	4	°C/W







### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	60	65		V
∆BVDSS/∆TJ	BVDSS Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.044		V/°C
		V <sub>GS</sub> =10V , I <sub>D</sub> =15A		28	36	mΩ
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =4.5V , I <sub>D</sub> =7A		38	45	mΩ
VGS(th)	Gate Threshold Voltage	V V 1 050 A	1.2	1.6	2.5	V
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=250uA$		-4.8		mV/°C
IDEE	Drain Source Leakage Current	V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =48V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA
IGSS	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =15A		25.3		S
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		2.5		Ω
Qg	Total Gate Charge (10V)	V <sub>DS</sub> =48V , V <sub>GS</sub> =10V , I <sub>D</sub> =15A		19		
Q <sub>gs</sub>	Gate-Source Charge		1	2.5		nC
$Q_{gd}$	Gate-Drain Charge		I	5		
Td(on)	Turn-On Delay Time		I	2.8		
Tr	Rise Time	$V_{DD}$ =30V , $V_{GS}$ =10V , $R_{G}$ =3.3 $\Omega$	I	16.6		ne
Td(off)	Turn-Off Delay Time	I <sub>D</sub> =15A	-	21.2		ns
T <sub>f</sub>	Fall Time			5.6		
C <sub>iss</sub>	Input Capacitance			1027		
Coss	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz	I	65		pF
Crss	Reverse Transfer Capacitance		I	46		
ls	Continuous Source Current <sup>1,6</sup>	\/-=\/-=0\/			20	Α
ISM	Pulsed Source Current <sup>2,6</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			40	Α
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C	-		1.2	V
t <sub>rr</sub>	Reverse Recovery Time	IF=15A , dI/dt=100A/μs ,	-	12.2		nS
Q <sub>rr</sub>	Reverse Recovery Charge	T <sub>J</sub> =25°C	1	7.3		nC

#### Note:

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- $\ensuremath{\mathsf{2}}_{\ensuremath{\mathsf{N}}}$  The data tested by pulsed , pulse width .The EAS data shows Max. rating .
- 3. The test cond  $\leq$  300us duty cycle  $\leq$  2%, duty cycle ition is TJ =25°C, VDD =48V, VG =10V, RG =25 $\Omega$ , L=0.1mH, IAS =13A
- 4. The power dissipation is limited by 175℃ junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



### **Typical Characteristics**

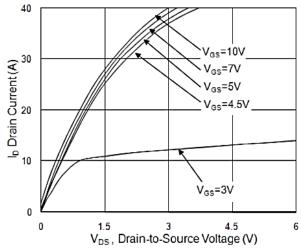


Fig.1 Typical Output Characteristics

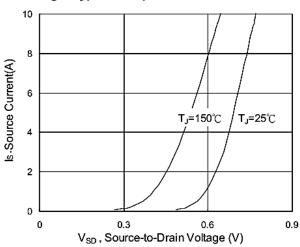


Fig.3 Forward Characteristics Of Reverse

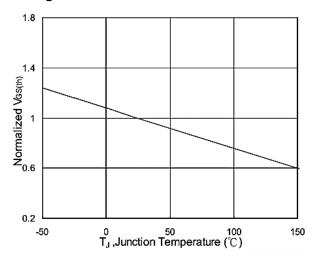


Fig.5 Normalized V<sub>GS(th)</sub> vs. T<sub>J</sub>

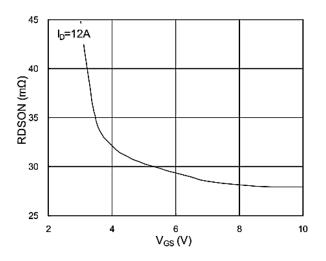


Fig.2 On-Resistance vs. Gate-Source

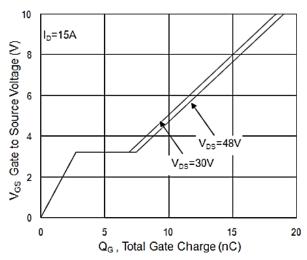


Fig.4 Gate-Charge Characteristics

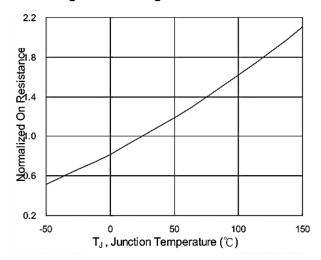


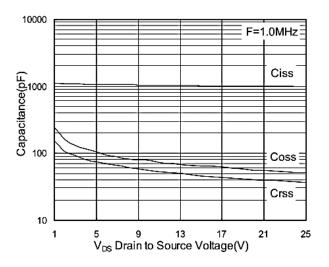
Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>





# AP30N06DF

### **60V N-Channel Enhancement Mode MOSFET**



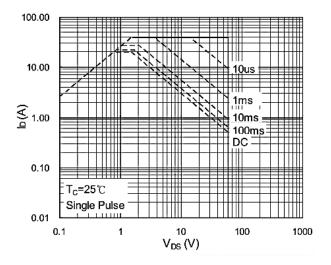


Fig.7 Capacitance

Fig.8 Safe Operating Area

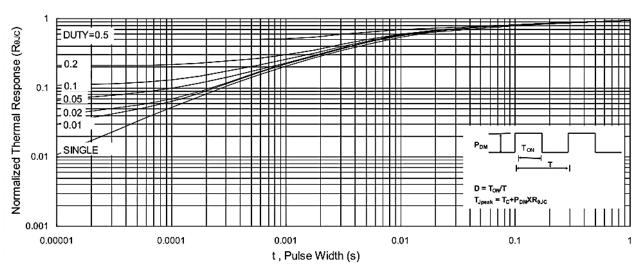
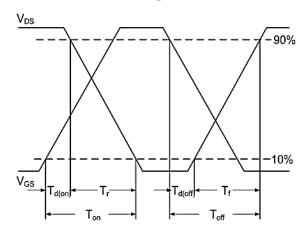


Fig.9 Normalized Maximum Transient Thermal Impedance





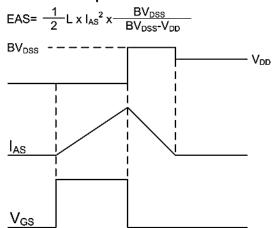
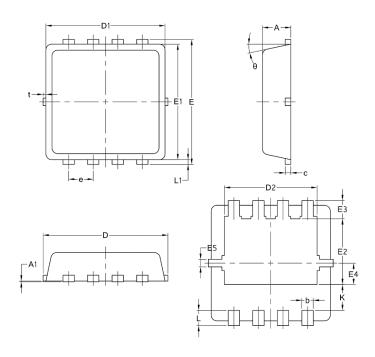


Fig.11 Unclamped Inductive Switching Waveform



# Package Mechanical Data-DFN3\*3-8L-JQ Single



	Common			
Symbol	mm			
	Mim	Nom	Max	
А	0.70	0.75	0.85	
A1	/	/	0.05	
b	0.20	0.30	0.40	
С	0.10	0.152	0.25	
D	3.15	3.30	3.45	
D1	3.00	3.15	3.25	
D2	2.29	2.45	2.65	
E	3.15	3.30	3.45	
E1	2.90	3.05	3.20	
E2	1.54	1.74	1.94	
E3	0.28	0.48	0.65	
E4	0.37	0.57	0.77	
E5	0.10	0.20	0.30	
е	0.60	0.65	0.70	
K	0.59	0.69	0.89	
L	0.30	0.40	0.50	
L1	0.06	0.125	0.20	
t	0	0.075	0.13	
Ф	10	12	14	



# AP30N06DF

#### 60V N-Channel Enhancement Mode MOSFET

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# AP30N06DF

## **60V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
Rve1.0	2021/10/23	Initial release

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